

N-Channel MOSFET MEM2302X

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General Description

MEM2302XG Series N-channel enhancement mode field-effect transistor ,produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation in a very small outline surface mount package.

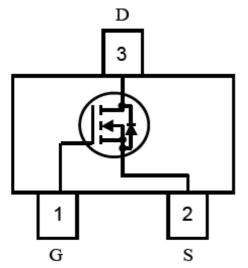
Features

• 20V/3A

 $\begin{array}{l} R_{DS(ON)} =& 29m\Omega @ V_{GS} =& 4.5V, \ I_{D} =& 3A \\ R_{DS(ON)} =& 36m\Omega @ V_{GS} =& 2.5V, \ I_{D} =& 2A \end{array}$

- High Density Cell Design For Ultra Low On-Resistance
- Subminiature surface mount package:SOT23

Pin Configuration



Absolute Maximum Ratings

Typical Application

- Battery management
- High speed switch
- Low power DC to DC converter

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V _{DSS}	20V	V
Gate-Source Voltage		V _{GSS}	±8	V
Drain	T _A =25℃	1	3	۸
Current	T _A =70℃	Ι _D	2	A
Pulsed Drain Current ^{1,2}		I _{DM}	15	А
Total Power	T _A =25℃	Pd	0.7	W
Dissipation	T _A =70℃	Fu	0.46	VV
operating junction temperature		Tj	150	°C
Storage Temperature Range		T _{stg}	-65/150	°C



Thermal Characteristics

Parameter	Symbol	Ratings	Unit	
Thermal Resistance, Junction-to-Ambient	RθJA	140	°C/W	

Electrical Characteristics

MEM2302X

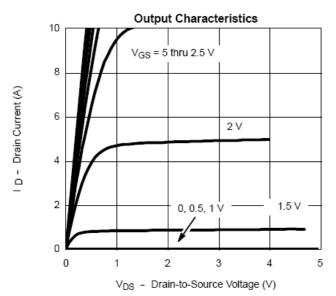
Parameter	Symbol	Test Condition	Min	Туре	Max	Unit				
Static Characteristics										
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} =0V, I _D =250uA	20	23		V				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=250$ uA	0.51	0.53	0.85	V				
Gate-Body Leakage	I _{GSS}	$V_{DS}=0V$, $V_{GS}=8V$		1.6	100	nA				
Gale-Douy Leakage		$V_{DS}=0V$, $V_{GS}=-8V$		-0.2	-100	nA				
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V V _{GS} =0V		6.3	1000	nA				
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =3A		29	50	mΩ				
Static Dialit-Source Off-Resistance		V _{GS} =2.5V, I _D =2A		36	65	mΩ				
Forward Transconductance	g fs	$V_{DS} = 5 V, I_{D} = 3.6A$		8		S				
Source-drain (diode forward) voltage	V_{SD}	V _{GS} =0V,I _D =1.25A	0.4	0.7	1	V				
	Dynamic	Characteristics								
Input Capacitance	Ciss	V _{DS} = 10 V,		300						
Output Capacitance	Coss	$V_{GS} = 0 V,$		120		pF				
Reverse Transfer Capacitance	Crss	f = 1 MHz		80						
Switching Characteristics										
Turn-On Delay Time	td(on)	$V_{DD} = 15 V,$ $R_L = 2.8\Omega$		8	15					
Rise Time	tr	I _D =3.6A		50	80	ns				
Turn-Off Delay Time	td(off)	$V_{GEN} = 4.5V,$		15	60					
Fall-Time	tf	Rg = 36Ω		10	25					
Total Gate Charge	Qg	V _{DS} = 10V,		4	10					
Gate-Source Charge	Qgs	$V_{GS} = 4.5 V,$		0.65		nc				
Gate-Drain Charge	Qgd	I _D = 3.6A		1.5						

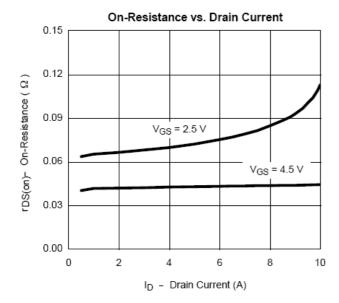
1. Repetitive rating, pulse width limited by junction temperature.

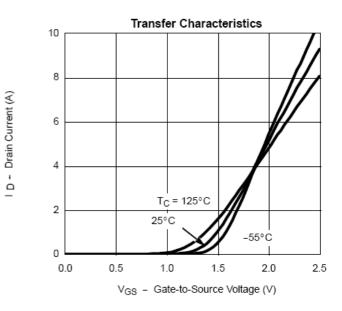
 2_{\times} Pulse width <300us , duty cycle <0.5%.

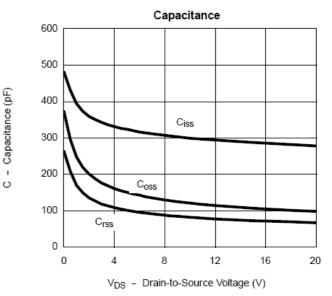


Typical Performance Characteristics

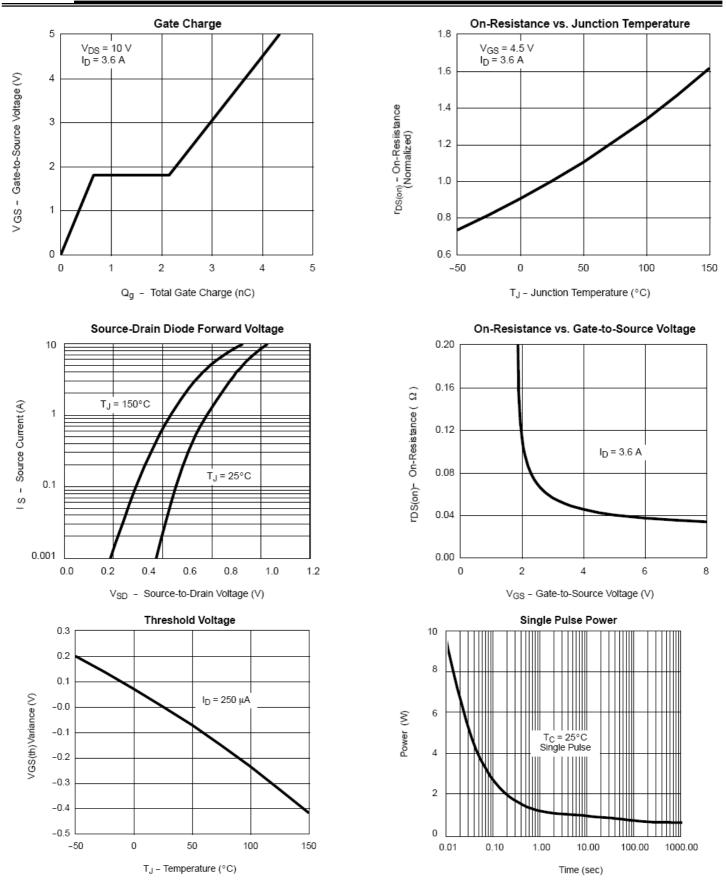




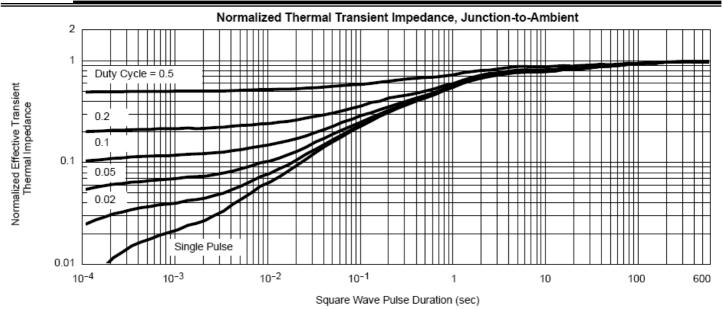






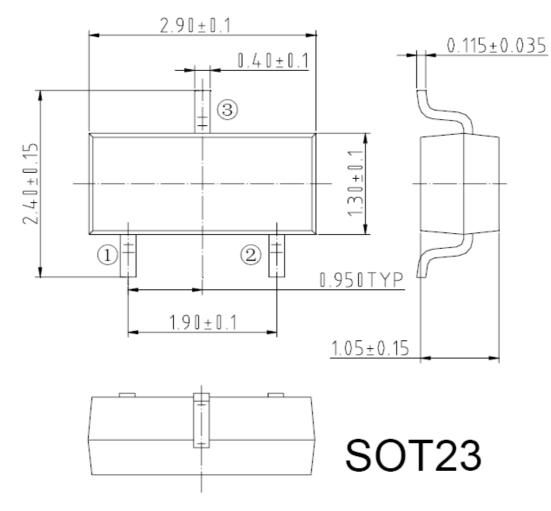








Package Information





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